

HiPerFET™ Power MOSFETs Single Die MOSFET

N-Channel Enhancement Mode Avalanche Rated, High dv/dt, Low t,

IXFN 80N48

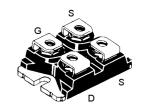
Preliminary data sheet

Test Conditions	Maximum Ratings		
T _J = 25°C to 150°C	480	V	
$T_J = 25$ °C to 150°C; $R_{GS} = 1 M\Omega$	480	V	
Continuous	±20	V	
Transient	±30	V	
T _c = 25°C, Chip capability	80	А	
$T_{\rm C}$ = 25°C, pulse width limited by $T_{\rm JM}$	320	Α	
$T_c = 25$ °C	80	Α	
T _c = 25°C	64	mJ	
T _c = 25°C	6	J	
$\begin{array}{ll} I_{S} & \leq I_{DM}, \text{ di/dt} \leq 100 \text{ A/}\mu\text{s}, \text{ V}_{DD} \leq \text{V}_{DSS}, \\ T_{J} & \leq 150^{\circ}\text{C}, \text{ R}_{G} = 2 \Omega \end{array}$	5	V/ns	
T _C = 25°C	700	W	
	-55 + 150	°C	
	150	°C	
	-55 + 150	°C	
50/60 Hz, RMS t = 1 min	2500 3000	V~ V~	
		Nm/lb.in.	
Terminal connection torque		Nm/lb.in.	
	30	g	
	$\begin{split} T_{_J} &= 25^{\circ}\text{C to } 150^{\circ}\text{C} \\ T_{_J} &= 25^{\circ}\text{C to } 150^{\circ}\text{C}; R_{_{GS}} = 1 \text{ M}\Omega \\ \\ &\text{Continuous} \\ &\text{Transient} \\ \\ T_{_C} &= 25^{\circ}\text{C}, \text{Chip capability} \\ T_{_C} &= 25^{\circ}\text{C}, \text{pulse width limited by } T_{_{JM}} \\ T_{_C} &= 25^{\circ}\text{C} \\ \\ T_{_J} &\leq 1_{_{DM}}, \text{di/dt} \leq 100 \text{A/μs}, \text{V}_{_{DD}} \leq \text{V}_{_{DSS}}, \\ T_{_J} &\leq 150^{\circ}\text{C}, R_{_G} = 2 \Omega \\ \\ T_{_C} &= 25^{\circ}\text{C} \\ \\ \hline \\ T_{_C} &= 25^{\circ}\text{C} \\ \\ \hline \\ T_{_{J}} &\leq 150^{\circ}\text{C}, R_{_{G}} = 2 \Omega \\ \\ \hline \\ T_{_{C}} &= 25^{\circ}\text{C} \\ \\ T_{_{C}} &= 25^{\circ}\text{C} \\ \\ \hline \\ T_{_{C}} &= 25^{\circ}\text{C} \\ \\ \hline \\ T_{$	$\begin{array}{cccccccccccccccccccccccccccccccccccc$	

Symbol	Test Conditions	Characteristic Values (T _J = 25°C, unless otherwise specified) min. typ. max.			
V _{DSS}	$V_{GS} = 0 \text{ V}, I_{D} = 3 \text{ mA}$	480			V
$V_{_{\mathrm{GH(th)}}}$	$V_{DS} = V_{GS}, I_{D} = 8 \text{ mA}$	2		4	V
I _{GSS}	$V_{GS} = \pm 20 V_{DC}, V_{DS} = 0$			±200	nΑ
I _{DSS}	$V_{DS} = V_{DSS}$ $V_{GS} = 0 V$	T _J = 25°C T _J = 125°C		100 2	μA mA
R _{DS(on)}	$V_{GS} = 10 \text{ V}, I_{D} = 0.5 \cdot I_{D25}$ Pulse test, t $\leq 300 \mu s$, duty cycle d $\leq 2 \%$			45	mΩ

 $V_{DSS} = 480 V$ $I_{D25} = 80 A$ $R_{--} = 45 m\Omega$

miniBLOC, SOT-227 B (IXFN) E153432



G = Gate D = Drain S = Source

Either Source terminal of miniBLOC can be used as Main or Kelvin Source

Features

- · International standard packages
- miniBLOC, with Aluminium nitride isolation
- Low $R_{DS (on)} HDMOS^{TM}$ process
- · Rugged polysilicon gate cell structure
- Unclamped Inductive Switching (UIS)
 rated
- · Low package inductance
- · Fast intrinsic Rectifier

Applications

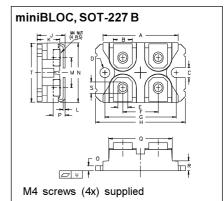
- DC-DC converters
- · Battery chargers
- Switched-mode and resonant-mode power supplies
- DC choppers
- · Temperature and lighting controls

Advantages

- · Easy to mount
- · Space savings
- · High power density



Symbol	Test Conditions $(T_{_{J}} = 25^{\circ}\text{C}, \text{ unle }$ min	ss otherwi	istic Values se specified) max.
g _{fs}	$V_{DS} = 15 \text{ V; } I_{D} = 0.5 \cdot I_{D25}, \text{ pulse test}$ 50	70	S
C _{iss})	9890	pF
C_{oss}	$V_{GS} = 0 \text{ V}, V_{DS} = 25 \text{ V}, f = 1 \text{ MHz}$	1750	pF
C_{rss}	J	460	pF
t _{d(on)})	61	ns
t _r	$V_{GS} = 10 \text{ V}, V_{DS} = 0.5 \cdot V_{DSS}, I_{D} = 0.5 \cdot I_{D25}$	70	ns
$\mathbf{t}_{d(off)}$	$R_{\rm G} = 1 \Omega \text{ (External)},$	102	ns
t,)	27	ns
Q _{g(on)})	380	nC
\mathbf{Q}_{gs}	$V_{GS} = 10 \text{ V}, V_{DS} = 0.5 \cdot V_{DSS}, I_{D} = 0.5 \cdot I_{D25}$	80	nC
\mathbf{Q}_{gd}	J	173	nC
R _{thJC}			0.18 KW
R _{thCK}		0.05	KW



Dim.	Millimeter		Incl	hes
	Min.	Max.	Min.	Max.
Α	31.50	31.88	1.240	1.255
В	7.80	8.20	0.307	0.323
С	4.09	4.29	0.161	0.169
D	4.09	4.29	0.161	0.169
E	4.09	4.29	0.161	0.169
F	14.91	15.11	0.587	0.595
G	30.12	30.30	1.186	1.193
Н	38.00	38.23	1.496	1.505
J	11.68	12.22	0.460	0.481
K	8.92	9.60	0.351	0.378
L	0.76	0.84	0.030	0.033
M	12.60	12.85	0.496	0.506
N	25.15	25.42	0.990	1.001
0	1.98	2.13	0.078	0.084
P	4.95	5.97	0.195	0.235
Q	26.54	26.90	1.045	1.059
R	3.94	4.42	0.155	0.174
S	4.72	4.85	0.186	0.191
Т	24.59	25.07	0.968	0.987
U	-0.05	0.1	-0.002	0.004

Source-Drain Diode

Characteristic Values

(T₁ = 25°C, unless otherwise specified)

Symbol	Test Conditions n	nin.	typ.	max.	
I _s	V _{GS} = 0 V			80	Α
I _{SM}	Repetitive; pulse width limited by $T_{\rm JM}$			320	Α
V _{SD}	$I_F = I_S, V_{GS} = 0 \text{ V},$ Pulse test, $t \le 300 \mu\text{s}, \text{ duty cycle d} \le 2 \%$			1.3	V
t _{rr} Q _{RM}	$I_F = 50A$, -di/dt = 100 A/ μ s, $V_R = 100 V$		1.2	250	ns μC Α

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